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Correlations between Structure, Composition and Electrical Properties of Tungsten /Tungsten Oxide Periodic Multilayers Sputter Deposited by Gas Pulsing

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Highlights

- W/WO_x multilayers were sputter deposited by the reactive gas pulsing process.
- Periodic sharp and smooth interfaces are produced through the film thickness.
- Correlations are established between structure, composition and electrical properties.
- Composition in sub-layers and at interfaces is connected to the bulk plasmon peak.

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